Search Notes

| Application/Control No. | Applicant(s)/Patent und Reexamination | er |
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| 10/766,487 | KOBAYASHI ET AL. | |
| Examiner | Art Unit | |
| David Buttner | 1712 | |

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| | DATE | EXMR |
| inventor search | 4/27/2006 | DB |
| east | 4/28/2006 | DB |
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